Inverted Metallurgical Microscopes ECLIPSE MA200/MA100N





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ECLIPSE MA200 MA100N

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Model features

MA200

Thanks to its unique, solid-box structure, the MA200 offers high stability, durability, and a smaller footprint than conventional models as well as easy access to the stage handle, the nosepiece, BF/DF change lever, and diaphragms located at front side.

Compatible		Brightfield	Darkfield	Simple polarizing	DIC	Fluorescence
observation methods		0	0	0	0	\bigcirc
	*DIA illuminator is available for transmitted light observation.					
Compatible illminators	 LV-LH50PC 12V50W Halogen Lamp Illuminator C-HGFI HG Precentered Fiber Illuminator (*option) 					
Magnification module	● 1x/1.5x/2x					
Compatible stages	 MA2-SR Mechanical Stage (stroke: 50 x 50 mm) 					

MA100N 📼

The MA100N is a compact inverted microscope designated for bright field and simple polarizing observations. This model offers cost-effective solution to manufacturing and QA/QC situations in industries, such as automotive/ electronic parts and industrial machinery/tools. This simple but durable microscope enables high contrast image observation and capture.



ECLIPSE MA200

New solution from Nikon: An ideal inverted microscope

Front Operation

All controls are on the front of the instrument. Delivers ease-of-use by placing all important controls on the front.





Automatically detects the address of the objective lens currently in use and displays it on the main unit front panel.

The observation position of the objective lens and sample can be checked easily from the microscope's front panel.

Box Structure

Smaller footprint than conventional models: Three times free spaces left! Improved durability thanks to the unique box structure.

Compact structure with a depth of 315 mm

A box shaped microscope, not only the width but also the depth is reduced dramatically: The foot print is only one-third of the conventional model!

High stability/durability

Vibration during high-power observation is reduced. Extremely high rigidity.

Evolved Optical Performance

Basic performance dramatically improved. Provides a more ergonomic and clear image observation.

Super-wide field of view

The ultra wide field of view eyepiece and with the combination of the newly developed 1x objective lens, a sample of 25mm diameter can be observed in an one field of view.





• T Plan EPI 1x Semi-Apochromat Wide field of view

Even Illumination

Improved uniformity of illumination delivers clear images, especially for digital imaging.

Combine up to eight images with the stitching feature

Combine up to eight images with the stitching feature. Get natural looking images with uniform lighting and no seams.





Combination with Digital Camera

Integration with digital camera for microscopy "Digigtal Sight series"

The MA200 allows detection of information and control of objective lenses via the camera control unit, enabling optimization of the conditions vital for image acquisition.



Accessory

Stage

The holder comes with a stage clip that enable sample rotation. This flexible handle stage delivers high durability needed to

support heavy samples.

1 MA-2 SR Stage



DIC

You can choose standard or high contrast type DIC prism for best match to the sample. It is effective for observation of minute step heights.



MA2-PA Unit 2 L-DIHC DIC Prism (High Contrast) L-DIC DIC Prism

Nosepiece & Magnification Module

Enables communication of objective lens position, magnification and intermediate magnification module information with the DS-L3 control unit and NIS-Elements image software.

1 MA2-MC Magnification Module

2 LV-NU5I Intelligent Universal Quintuple Nosepiece



Holders

We offer a full lineup of holders that correspond to a variety of sample shapes.



Polarizing

Polarizing observation is effective for birefringence samples. MA2-PA unit is suitable for observation of aluminium.

• Single-action operation Links the attachment/release of the analyzer/polarizer.

MA2-PA Unit
 MA2-UPA Unit*
 MA2-λP λ Plate
 *It is suitable for inspecting aluminium sample.



Aluminium sample



Grain Size Reticle & Scale

Overlays a pattern onto the observed image. MA2-GR Grain Size Reticle is used for grain size analysis which is compliant to JIS G0551 and ASTM E112 standards. The MA2-MR Scale is used for scale display for each objective magnification.

 MA2-GR Grain Size Reticle JIS G0551/objective lense 10x (100x magnification) ASTM E112/objective lense 10x (100x magnification)
 MA2-MR Scale



MA100N

Introducing a durable, user-friendly Inverted Microscope with superior image quality, a small footprint and great cost performance.

The MA100N is a compact inverted microscope designated for bright field and simple polarizing of industries, Nikon developed this simple but durable model which enables high contrast image frequent lamp replacement.

Illumination

Employment of high-intensity LED illumination (Eco-illumination)

Compared to conventional halogen illumination, these high intensity LED sources need only about one third of consuming electricity and last approximately 30 times longer. The MA100N ensures stable sample observation with uniform color temperature even in different light intensity.



Compact Body

Redesign to 11% smaller than the conventional models

The MA100N is a model designated for LED illumination, which enables to save about 11% of footprint and allows users to have more installation choices.





Stage

Stable control even with heavy samples A newly developed stage boasting superior durability

Nikon developed the new MA-SR-N Rectangular Stage especially for the MA100N. The three-plate structure gives the microscope superior control and durability for observation of heavy samples, such as a grinder resin mounted samples.



Aperture Diaphragm

Aperture diaphragm coming standard

The epi illuminator comes standard with a variable aperture diaphragm to control image contrast and depth of field.



Previous model (MA100L)



observations. Responding to the requests from manufacturing and QA/QC sections in a variety observation and capture. Further, the high intensity LED illumination reduces the need for



Accessory

CFI60-2

Nikon's CFI60 optical system, highly evaluated for its unique concept of high NA combined with long working distance has further evolved to achieve the apex in long working distance and chromatic aberration correction.

Standard objective lenses

TU Plan Fluor Series EPI/BD 5x/10x/20x/50x/100x



These universal type standard objective lenses enable brightfield, darkfield, simple

polarizing, sensitive polarizing, differential interference, and epi-fluorescence observation in one lens.





* Depicted is the brightfield observation (EPI) objective lens

Model	Magnification	NA	Working Distance (mm)
TU Plan Fluor EPI	5×	0.15	23.5
(brightfield type)	10×	0.30	17.5
	20×	0.45	4.5
	50×	0.80	1.0
	100×	0.90	1.0
TU Plan Fluor BD	5×	0.15	18.0
(brightfield/ darkfield type)	10×	0.30	15.0
	20×	0.45	4.5
	50×	0.80	1.0
	100×	0.90	1.0

Long working distance objective lenses



Through the use of phase Fresnel lenses, these

objective lenses enable long working distances while offering higher-level

chromatic aberration correction than conventional objective lenses. This further improves operability for samples with differences in level.



Long

WD

Sem

apo

Light weight

* Depicted is the brightfield observation (EPI) objective lens.

Model	Magnification	NA	Working Distance (mm)
TU Plan EPI ELWD	20×	0.4	19.0
(brightfield type)	50×	0.6	11.0
	100×	0.8	4.5
TU Plan BD ELWD	20×	0.4	19.0
(brightfield/ darkfield type)	50×	0.6	11.0
	100×	0.8	4.5

Low-magnification objective lenses

These low-magnification objective



lenses enable clear observation using a conventional analyzer/polarizer, as well as operability-oriented observation without need for an analyzer/polarizer.

Model	Magnification	NA	Working Distance (mm)
T Plan EPI	1×	0.03	3.8
(brightfield type)	2.5×	0.075	6.5

Apochromatic objective lenses TU Plan Apo Series

EPI/BD 50x/100x/150x



By using phase Fresnel lenses, these objective lenses achieve significantly longer operating distances while maintaining the superior chromatic aberration performance of apochromatic lenses. A 50x lens is new to the line-up.

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* Depicted is the brightfield observation (EPI) objective lens.

Model	Magnification	NA	Working Distance (mm)
TU Plan Apo EPI	50×	0.8	2.0
(brightfield type)	100×	0.9	2.0
	150×	0.9	1.5
TU Plan Apo BD	50×	0.8	2.0
(brightfield/ darkfield type)	100×	0.9	2.0
	150×	0.9	1.5

Other Lens Brightfield objective lense CFI L Plan EPI 40x

A 40x objective lens is best for metal analysis.

NA: 0.65 W.D.: 1.0mm



Digital cameras for microscopes JIGITAL SIGHT SERIES Stand-Alone Model Microscope camera Microscope camera DS-Fi3 📖 DS-Ri2 Capable of expressing images as is, this Three main features of microscope digital camera offers high the previous models. Nikon resolution, color reproduction, and frame high-resolution, high rate. The Stand-Alone Model is capable sensitivity and low of high-definition image acquisition noise, and high-speed without a control unit. live display are offered in 1 camera. High-High-16.25 Color Color resolution resolution Frame Rate 45fps (1636×1088) 30fps (1440×1024) Max Recordable Pixels 4908×3264 2880×2048

Microscope camera control unit

DS-L4 🖤

DS-Fi3 can be optionally connected to theDS-L4 tablet-style control unit, eliminating the need and space requirements of a desktop PC. DS-L4 has a large number of built-in security for network connectivity.

Scene Mode

Optimal imaging parameters for each sample type and observation method can easily be set through the icons.

Variety of Tool Features

Enables easy measurements directly on images, with input of lines and comments. These can also be written and saved with the image, and measurement data can also be output.

Measurement (two-point distance)



Imaging software NIS-Elements series



Image Stitching

Stitches together images acquired from multiple fields of view to create one image.



EDF (Extended Depth of Focus) Create a single, all-in-focus image from images of differing focus.



* See the "Digital Camera Digital Sight Series for Microscopes" catalog for details on Digital Sight features.

Wafer/IC

Circuit board

Flat Panel Display

Metal, Ceramic/Plastic





Dimensions





Specifications (MA200)

		MA200		
Main body	Focusing mechanism	Focusing nosepiece (Fixed stage) Coaxial coarse/fine adjustment knob (torque adjustable)		
		Coarse adjustment of 4.0 mm per rotation, fine adjustment of 0.2 mm per rotation		
	Illumination	With flare prevention, Built in UV cut filter		
		Field diaphragm: dialing continuous variable (centerable), Aperture diaphragm: dialing continuous variable (centerable)		
		Filter: Double turret (ND16, ND4/GIF, NCB, Additional option available), Polarizing block (Selectable with or without 1/4 λ Plate)		
		Fluorescence filter blocks: B/G/V/BV, Built in 12V50W halogen lamp, C-HGFI HG Fiber Illuminator		
	Light distribution	Eyepiece tube/Back port: 100/0, 55/45		
Optics	CFIeo/CFIeo-2 system			
Observation image	Surface Image			
Observation method	Bright/Darkfield/Simple Polarizing/DIC/Epi-Fluorescence			
Revolving nosepieces LV-NU5I: Bright/Darkfield/DIC 5 position nosepiece, LV-NU5A: Motorized Bright/Darkfield/DIC 5 position		d/DIC 5 position nosepiece, LV-NU5A: Motorized Bright/Darkfield/DIC 5 position nosepiece		
	MA-N7-I Brightfield 7 position nosepiece (Intelligent)			
Stage	MA2-SR Mechanical Stage (X/Y flexible handle)			
	Dimension: 295×215mm, Stroke: 50mm×50mm (with distance graduation), Standard accessory: ø22 universal specimen holder (with sample clip)			
Trinocular eyepiece	Seidentopf, interpupillary distance adjustment 50-75mm			
Power input	100-240V, 50-60Hz			
Electric power consumption	1.2A 75W			
Weight	Approx. 26 kg (depends on combination)			
Option	Intermediate magnification	Turret (1x, 1.5x, 2x), Status detection (Output magnification information to main unit)		
	Scale	MA2-GR Grain Reticle (ASTM E112-63 grain sizing numbers 1 to 8), Grid Reticle(20 lines, 0.5mm)		
		MA2-MR Scale Reticle (compatible with 5-100x, Read in um, Dialing System)		

Specifications (MA100N)

	MA 100N			
Optics	CFIe0/CFIe0-2 system			
Observation image	Reversed image			
Observation method	Brightfield and polarization (with MA P/A simple polarizer/analyzer set)			
Focusing	Focusing nosepiece (fixed stage), coaxial coarse/fine adjustment knob with 8.5-mm stroke			
	(Coarse adjustment of 37.7mm per turn, fine adjustment of 0.2mm per turn)			
Nosepiece	Brightfield 5-position nosepiece			
Stage	MA-SR-N Rectangular 3-plate Stage N: 50×50 mm stroke (includes two stage inserts (ø20mm and 40mm opening) and coaxial control handle on the right side			
	The 3-plate design allows entire top surface to move. Optional Stage inserts: MA-SRSH1 Specimen Holder 1 with (ø15mm opening or MA-SH3			
	Specimen Holder 3 with 2mm to 32mm adjustable opening			
	MA-SP-N Plain Stage N: 188×310mm - Includes two stage inserts (1) clear acrylic stage insert with ø30mm opening, (2) clear acrylic stage insert			
	with crescent opening (width 30mm) to allow clearance for rotation of high magnification objectives			
	Optional stage inserts: MA-SRSH1 Specimen Holder 1 with 15mm opening or MA-SH3 Specimen Holder 3 with 2mm to 32mm adjustable opening			
	Accepts Attachable Mechanical Stage TI-SM			
	TS2-S-SM Mechanical Stage: 126mm×78mm stroke, handle can be attached on the right or left side of the plain stage			
	Optional Specimen Holders to fit Attachable Mechanical stage: MA-SH1-N Specimen Holder 1N (ø15mm opening)			
	MA-SH2-N Specimen Holder 2N (ø30mm opening), or C-S-HU Universal Holder (30mm to 65mm adjustable opening)			
Illuminator	Internal power supply white LED light source, condenser built-in (lever operated), ø25mm filter can be inserted			
Binocular body	Built-in Siedentopf binocular, 45 inclination angle and 50 to 75-mm interpupillary adjustment, attachable camera port, eyepiece/Port: 100/0:0/100			
Power consumption (max.)	15W			
External dimensions	229x551x404 mm (WxDxH)			
Weight	Approx. 10kg			

Specifications and equipment are subject to change without any notice or obligation on the part of the manufacturer. April 2017 ©2006-2017 NIKON CORPORATION N.B. Export of the products* in this catarog is controlled under the Japanese Foreign Exchange and Foreign Trade Law. Appropriate export procedures shall be required in case of export from Japan. *Products: Hardware and its technical information (including software)

	TO ENSURE CORRECT USAGE, READ THE CORRESPONDING MANUALS CAREFULLY BEFORE USING THE EQUIPMENT.
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